Monolithic Diode Array

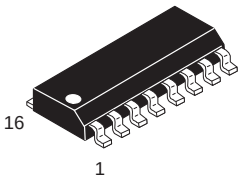
Surface Mount Isolated 8–Diode Array

MMAD1108

Motorola Preferred Device

This diode array is a multiple diode junction fabricated by a planar process and mounted in integrated circuit packages for use in high–current, fast–switching core–driver applications. This array offers the advantages of an integrated circuit with high–density packaging and improved reliability. This advantage results from such factors as fewer connections, more uniform device parameters, smaller size, less weight and fewer glass–to–metal seals.

- Designed for use in Computers and Peripheral Equipment
- Applications Include:
  - Magnetic Cores
  - Thin–Film Memories
  - Plated–Wire Memories
  - Decoding or Encoding

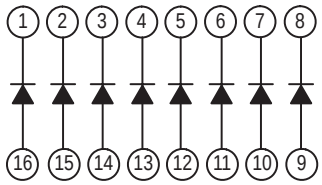


CASE 751B–05
SO–16

MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Peak Reverse Voltage	V_{RM}	50	Vdc
Steady–State Reverse Voltage	V_R	50	Vdc
Peak Forward Current 25°C	I_{FM}	500	mAdc
Continuous Forward Current	I_F	400	mAdc
Power Dissipation Derating Factor	P_D	500 4.0	mW mW/°C
Operating Temperature	T_A	–65 to +150	°C
Storage Temperature Range	T_{stg}	–65 to +150	°C

PIN CONNECTION DIAGRAM



ELECTRICAL CHARACTERISTICS (@ 25°C Free–Air Temperature)

Characteristic	Symbol	Limit		Unit
		Min	Max	
Reverse Breakdown Voltage(1) (I_R = 10 μAdc)	$V_{(BR)}$	50	—	Vdc
Static Reverse Current (V_R = 40 Vdc)	I_R	—	0.1	μAdc
Static Forward Voltage (I_F = 100 mAdc) (I_F = 500 mAdc)(2)	V_F	 — —	 1.2 1.6	Vdc
Peak Forward Voltage(3) (I_F = 500 mAdc)	V_{FM}	—	5.0	Vdc

NOTES:
1. This parameter must be measured using pulse techniques. PW = 100 μs, duty cycle ≤ 20%.
2. This parameter is measured using pulse techniques. PW = 300 μs, duty cycle ≤ 2.0%. Read time is 90 μs from the leading edge of the pulse.
3. The initial instantaneous value is measured using pulse techniques. PW = 150 ns, duty cycle ≤ 2.0%, pulse rise time ≤ 10 ns. The total capacitance shunting the diode is 19 pF maximum and the equipment bandwidth is 80 MHz.

Preferred devices are Motorola recommended choices for future use and best overall value.

REV 1

ELECTRICAL CHARACTERISTICS (@ 25°C Free–Air Temperature) (Continued)

Characteristic	Symbol	Typical Value	Unit
SWITCHING CHARACTERISTICS (@ 25°C Free–Air Temperature)			
Forward Recovery Time (I_F = 500 mAdc)	t_{fr}	20	ns
Reverse Recovery Time (I_F = 200 mA, I_{RM} = 200 mA, R_L = 100 Ω, i_{rr} = 20 mA)	t_{rr}	8.0	ns

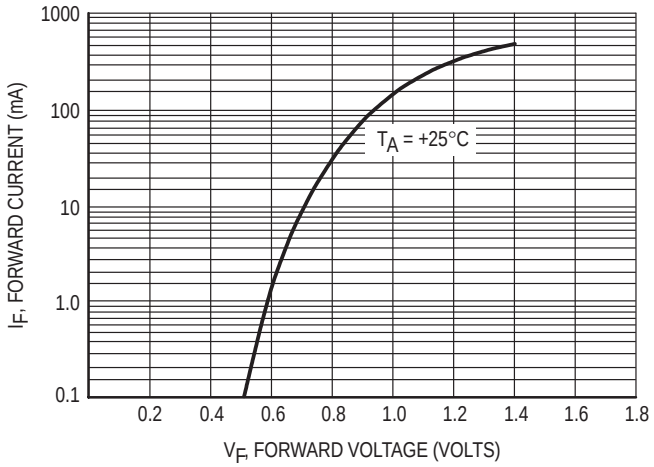


Figure 1. Typical Characteristics Static Forward Voltage

TEST PROCEDURE FOR MULTIPLE DIODES

1.0. REVERSE BIAS TESTING

1.1. LEAKAGE

Regardless of device configuration type, when testing any reverse bias condition, the forcing power supply must be applied only to the uncommon terminal of the pair. As in Figure 1, this would be pins 1 and 14. This can be referred as the high side of the test circuit. The low side of the test circuit must be connected to the common terminal of the pair which in most testers is where the current measurement is taken. This method is used to eliminate the possibility of degrading the diode in that pair which is not under test. Diode arrays with multiple pairs such as the MMAD1103, also have leakage paths in the die between common terminals of the pairs. To isolate the device under test so that the leakage from the other pairs in the package do not affect the test result, the leakage current from the common terminals of the pairs not under test must be shunted to measurement common. Figure 1 shows the test configuration for both of these cases.

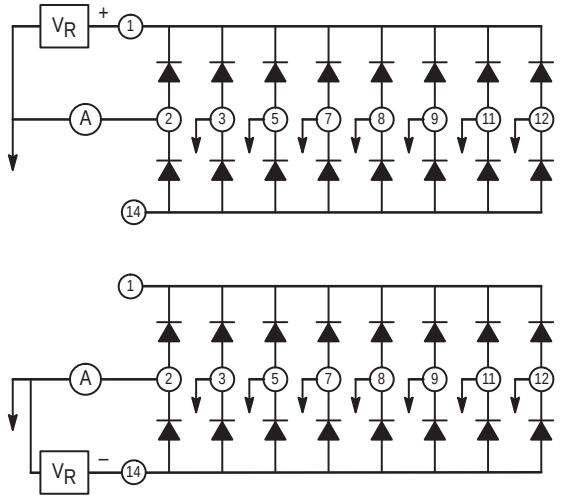


Figure 1

1.2. BREAKDOWN

It is not recommended to test breakdown on these devices due to the possibility of degrading the device. Breakdown may be checked on a curve tracer but extreme caution should be used.

2.0. FORWARD BIAS TESTING

Diode arrays are designed with the pairs in parallel; therefore, care must be taken to prevent the other diodes in the array from affecting the measured value of the diode under test. Figure 2 illustrates the proper technique to measure only the correct value of the diode under test.

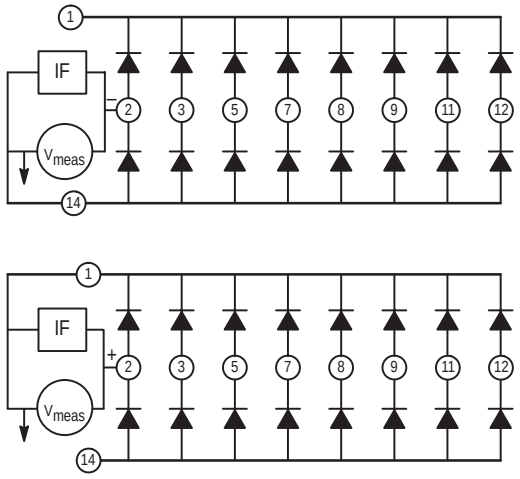


Figure 2

2.1. KELVIN CONNECTION

To achieve the best possible accuracy when testing bias currents over 10 mA, Kelvin connection to the leads of the device under test is mandatory. True Kelvin connection dictates that two test connections are made directly to the leads of the device. One is for power which is the bias supply, and the other is for sense which is for the measurement circuit. Kelvin connections are used to eliminate the effects of the connection resistance between the lead of the device and the contacts of the test handler and/or hand fixture. Figure 3 is an example of Kelvin connection.

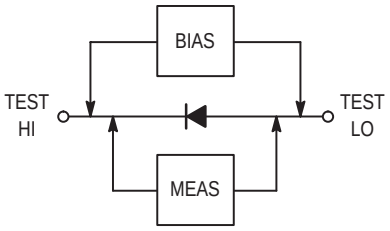


Figure 3

2.2. PULSE TESTING

When testing bias currents over 10 mA, pulse testing should be used to minimize thermal drift of the measured value. The pulse width of a pulse test is approximately 300 μs to 380 μs.

3.0. TESTING PROTOCOL

3.1. TEST TYPES

When testing in sequence all of the electrical characteristics, all reverse bias conditions should be tested before the forward bias conditions are tested.

3.2. BIASING MAGNITUDES

Tests of the same test type should be grouped together with the bias conditions in ascending order. For example:

V_F @ 10 mA < 0.6 V
V_F @ 50 mA < 0.8 V
V_F @ 100 mA < 1 V
V_F @ 500 mA < 1.5 V